

Magnetic force microscopy of domain wall stray fields on single-crystal iron whiskers

T. Göddenhenrich, H. Lemke, U. Hartmann and C. Heiden

Using a capacitively controlled force microscope we have imaged typical domain wall configurations like 90° closure structures and subdivided 180° wall segments in single-crystal iron whiskers. Differences in wall contrast between 90° and 180° domain walls are clearly observed. The effect of tip-to-sample distance on lateral resolution and wall contrast in magnetic force microscopy is shown.